A Framework for Evaluation of Side-channel Leakage in a RISC-V Processor

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Differential Power Analysis(DPA)

> Kocher et al.¹ introduced DPA that measures power consumption of a device to reveal secret information



¹Paul Kocher, Joshua Jaffe, and Benjamin Jun. "Differential power analysis". In: Annual International Cryptology Conference. Springer. 1999, pp. 388–397.

Attack Scheme

Figure 1: Correlating hypothetical power with measured power traces

Attack Scheme

$$\begin{pmatrix} h_{1,1} & h_{1,2} & \dots & h_{1,K} \\ h_{2,1} & h_{2,2} & \dots & h_{2,K} \\ \vdots & \vdots & \ddots & \vdots \\ h_{N,1} & h_{N,2} & \dots & h_{N,K} \end{pmatrix} \qquad \begin{pmatrix} t_{1,1} & t_{1,2} & \dots & t_{1,T} \\ t_{2,1} & t_{2,2} & \dots & t_{2,T} \\ \vdots & \vdots & \ddots & \vdots \\ t_{N,1} & t_{N,2} & \dots & t_{N,T} \end{pmatrix}$$

Figure 2: Correlating hypothetical power with measured power traces

Result of DPA on AES-128 Encryption

First byte of the key = 19



Motivation

Can we identify the processor components which causes leakage?

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Step 1: Power patterns need to be identified

- Step 2: Quantify the leakage
- Step 3: Pinpointing the source of leakage

Total power = Static power + Dynamic power



Dynamic power is only when switching Leakage power is permanent

Figure 3: Power consumption in CMOS circuit

Capturing Power Patterns



Figure 4: Hamming-distance model

Quantifying Leakage

Side-channel Vulnerability Factor (SVF)²



² John Demme et al. "Side-channel vulnerability factor: A metric for measuring information leakage". In: ACM SIGARCH Computer Architecture News 40.3 (2012), pp. 106–117.

Setup

- ➣ Target Processor: SHAKTI C-Class³
- > 64 bit, 6-stage pipeline which supports RISC-V ISA
- Benchmark program: AES-128 encryption compiled using riscv-gcc⁴ compiler version 5.4.0

³Neel Gala et al. "SHAKTI Processors: An Open-Source Hardware Initiative". In: *VLSID*. 2016, pp. 7–8.
⁴Andrew Waterman et al. *The RISC-V Instruction Set Manual. Volume 1: User-Level*

ISA, Version 2.0. Tech. rep. DTIC Document, 2014.

Methodology

- > Formation of HD Matrix
- ➢ Feature Analysis
- > Correlation Analysis

Formation of HD Matrix

> Value Change Dump(VCD) files are collected for n samples



Figure 5: Formation of HD matrix from data matrix

Feature Analysis

- Every feature of HD matrix(Side-channel) is correlated with HD vector of actual data(oracle) using Pearson's correlation coefficient
- > Features having high correlation are selected for further analysis

Correlation Analysis



Figure 6: Leakage analysis of a module

Results



Figure 7: Leakages during AES-SubBytes operation in SHAKTI C-Class components

Results



Figure 8: Leakages during AES-MixColumns operation in SHAKTI C-Class components



Figure 9: Leakages found in FPU module after 1^{st} round SubByte operation

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Expected and Unexpected Leakage

Expected Modules that Leak

- 🗸 Data Cache
- ✓ Register File
- 🖌 ALU
- ✓ Pipeline Buffers

Unexpected Modules that Leak

- ✓ Floating Point Unit
- Instruction Memory
- Branch Prediction Unit

Unexpected Leakage Analysis

- > ff_input\$D_IN[211:0] signal in FPU leaks data from register file.
- MayBe# construct in Bluespec System Verilog leaks data though the validating condition fail. Adding control bits(0/1) with data and passing it

Work In Progress

- Adding Side-channel countermeasures for leaking modules such as dcache, fpu, imem, bpu etc
- > In order to improve Side-channel security of the system, adding power analysis validations at the development stage
- > Validate the device against public key ciphers such as RSA, ECC

Thank you Any Questions…?